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Erratum

Erratum to "Influence of thermal treatment on the ion-storage capacity of Ce oxide and Ce–V mixed oxide films" [Thermochim. Acta 411 (2004) 211–217]☆

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The publisher regrets that in the original printing of the above article Figs. 1–3 were printed incorrectly. The correct figures are in the following pages.

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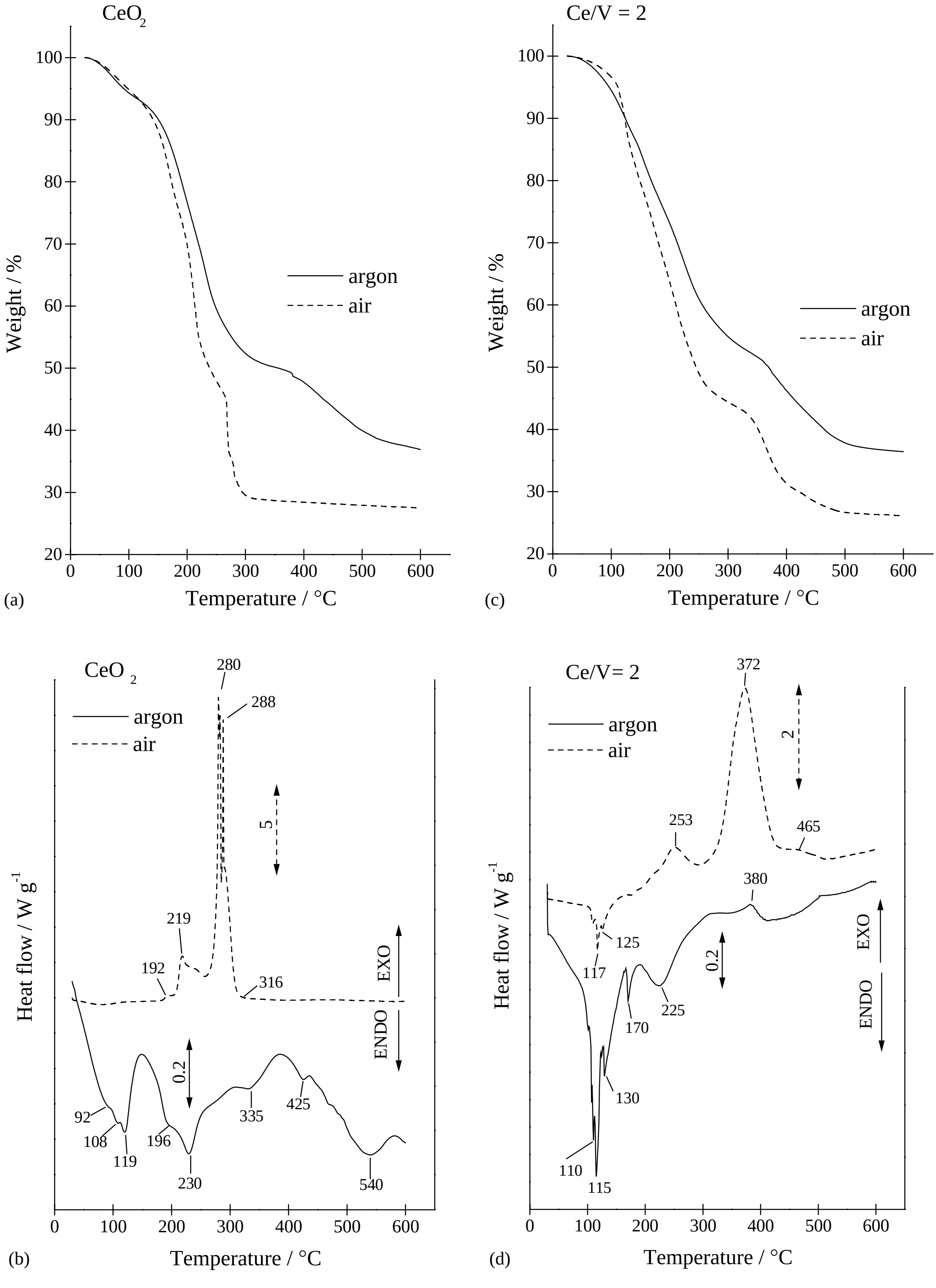

Fig. 1. Dynamic TG and DSC curves of CeO_2 (a and b) and Ce/V = 2 (c and d) xerogels annealed in argon and air atmospheres.

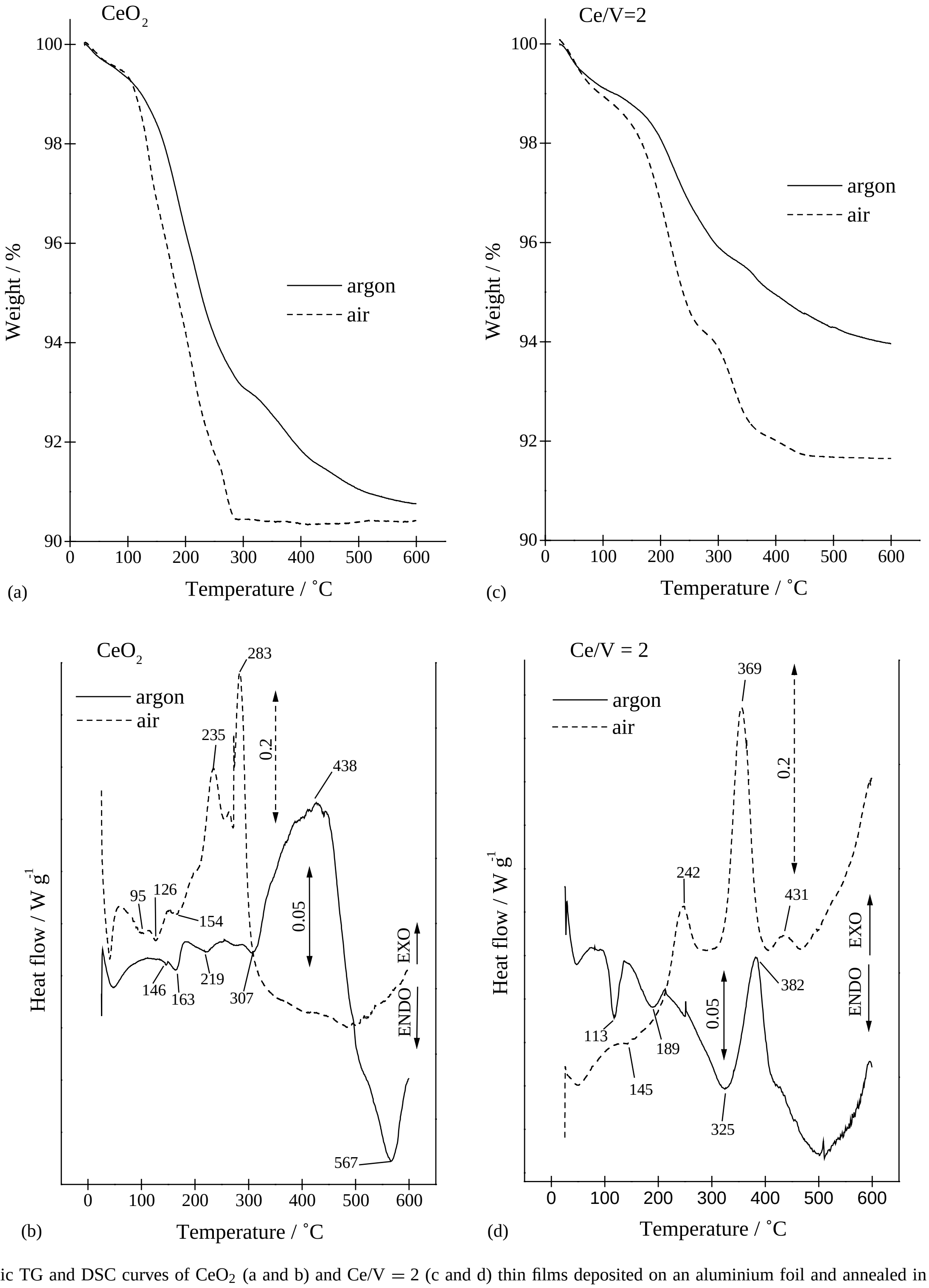

Fig. 2. Dynamic TG and DSC curves of CeO$_2$ (a and b) and Ce/V = 2 (c and d) thin films deposited on an aluminium foil and annealed in argon and air atmospheres.

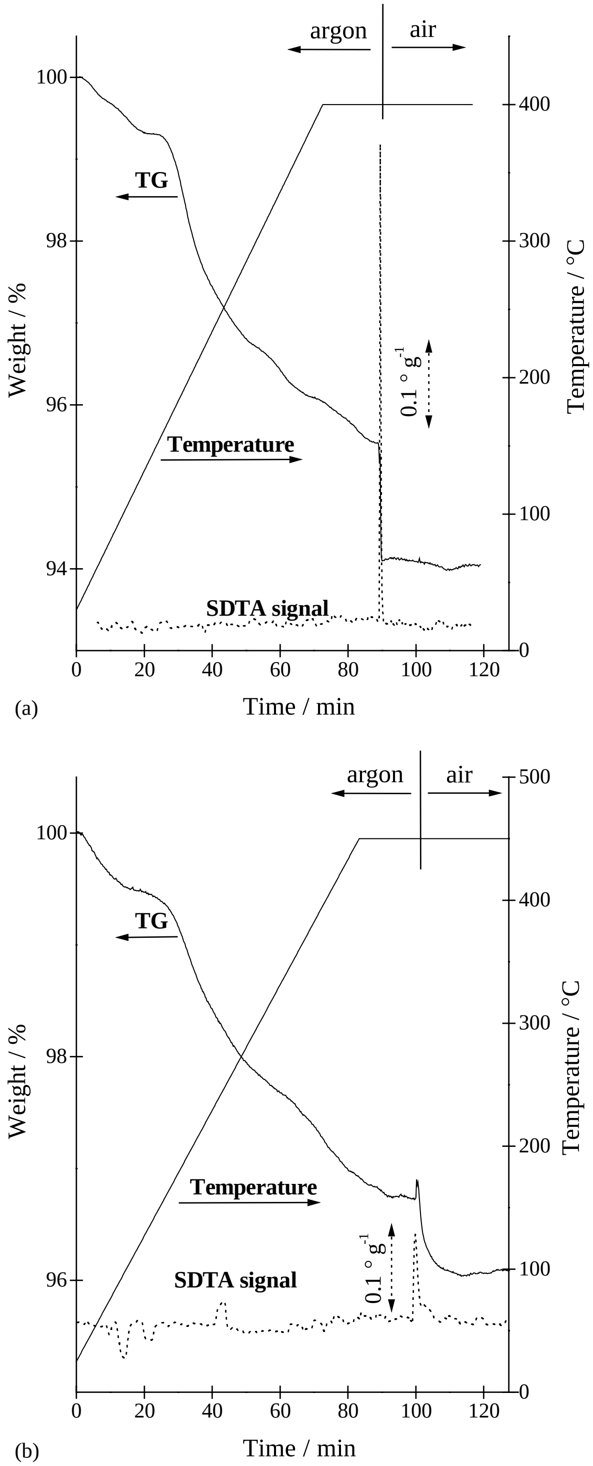

Fig. 3. TG/SDTA curves of CeO_2 (a) and Ce/V = 2 (b) thin films heat-treated in an argon atmospheres between 25 and 400 °C (CeO_2 samples) or 25 and 450 °C (Ce/V = 2 samples) and isothermally treated at the final temperature for 15 min. The purge gas was then switched to an air atmospheres.